



型号: SLS65N06

60V N-Channel Enhancement Mode MOSFET

The SLS65N06DF uses advanced **APM-SGT I** technology to provide excellent RDS(ON), low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

主要特性/Features

N-MOSFET

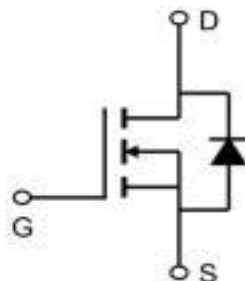
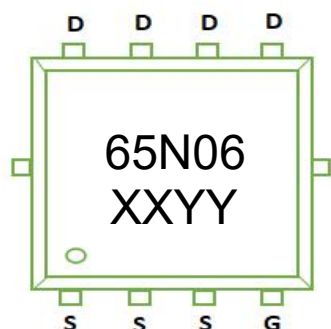
VDS = 60V ID =65A

RDS(ON) < 10mΩ @ VGS=10V (Type: 7.5mΩ)

应用/Application

Battery Switch .
Load switch .
Power management.
Uninterruptible power supply

印字/MARKING 等效电路/Equivalent Circuit





极限参数/ P-MOSFET Absolute Maximum Ratings(TA=25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
VDS	Drain source voltage	60	V
VGS	Gate source voltage	±20	V
I _D @T _A =25°C	Continuous drain current	60	A
I _D @T _A =70°C	Continuous drain current	31	A
IDM	Pulsed drain current	60	A
P _D @T _A =25°C	Power dissipation	60	W
EAS	Single pulsed avalanche energy	30	mJ
TSTG	Storage Temperature Range	-55 to 150	°C
T _j	Operation and storage temperature	-55 to 150	°C
R _{θJC}	Thermal resistance, junction-case	2.1	°C/W
R _{θJA}	Thermal resistance, junction-ambient ⁵⁾	85	°C/W



电性能参数/ P-MOSFET Electrical Characteristics (TA=25°C unless otherwise noted)

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Unit
BVDSS	Drain-source breakdown voltage	$V_{GS}=0\text{ V}$, $I_D=250\text{ }\mu\text{A}$	60	68		V
VGS(th)	Gate threshold voltage	$V_{DS}=V_{GS}$, $I_D=250\text{ }\mu\text{A}$	1.2	1.5	2.5	V
RDS(ON)	Drain-source on-state resistance	$V_{GS}=10\text{ V}$, $I_D=20\text{ A}$		7.5	10	m Ω
RDS(ON)	Drain-source on-state resistance	$V_{GS}=4.5\text{ V}$, $I_D=10\text{ A}$		10	13	m Ω
IGSS	Gate-source leakage current	$V_{GS}=\pm 20\text{ V}$			± 100	nA
IDSS	Drain-source leakage current	$V_{DS}=60\text{ V}$, $V_{GS}=0\text{ V}$			1	μA
Ciss	Input capacitance	$V_{GS}=0\text{ V}$, $V_{DS}=50\text{ V}$, $f=100\text{ kHz}$		1182.1		pF
Coss	Output capacitance			199.5		pF
Crss	Reverse transfer capacitance			4.1		pF
td(on)	Turn-on delay time	$V_{GS}=10\text{ V}$, $V_{DS}=50\text{ V}$, $R_G=2\text{ }\Omega$, $I_D=10\text{ A}$		17.9		ns
tr	Rise time			4.0		ns
td(off)	Turn-off delay time			34.9		ns
tf	Fall time			5.5		ns
Qg	Total gate charge	$I_D=10\text{ A}$, $V_{DS}=50\text{ V}$, $V_{GS}=10\text{ V}$		18.4		nC
Qgs	Gate-source charge			3.3		nC
Qgd	Gate-drain charge			3.1		nC
Vplateau	Gate plateau voltage			2.8		V
Is	Diode forward current	$V_{GS}<V_{th}$			60	A
ISP	Pulsed source current				180	
VSD	Diode forward voltage	$I_S=20\text{ A}$, $V_{GS}=0\text{ V}$			1.3	V
trr	Reverse recovery time	$I_S=10\text{ A}$, $di/dt=100\text{ A}/\mu\text{s}$		41.8		ns
Qrr	Reverse recovery charge			36.1		nC
Irrm	Peak reverse recovery current			1.4		A

Note

- 1、 Calculated continuous current based on maximum allowable junction temperature.
- 2、 Repetitive rating; pulse width limited by max. junction temperature.
- 3、 Pd is based on max. junction temperature, using junction-case thermal resistance.
- 4、 $V_{DD}=50\text{ V}$, $R_G=50\text{ }\Omega$, $L=0.3\text{ mH}$, starting $T_j=25\text{ }^\circ\text{C}$.
- 5、 The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_a=25\text{ }^\circ\text{C}$.



典型特性/ Typical Characteristics

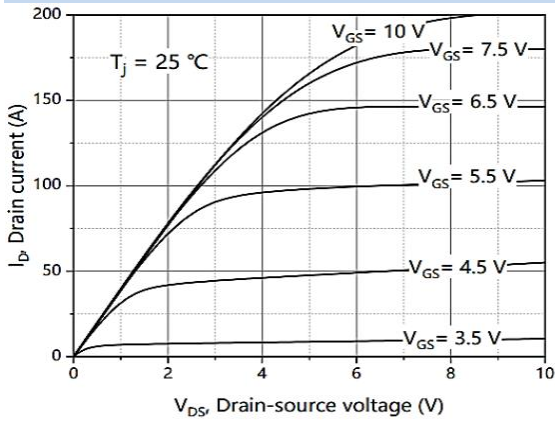


Figure 1. Typ. output characteristics

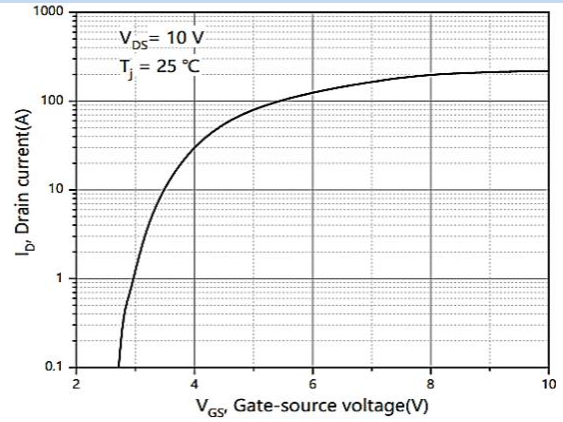


Figure 2. Typ. transfer characteristics

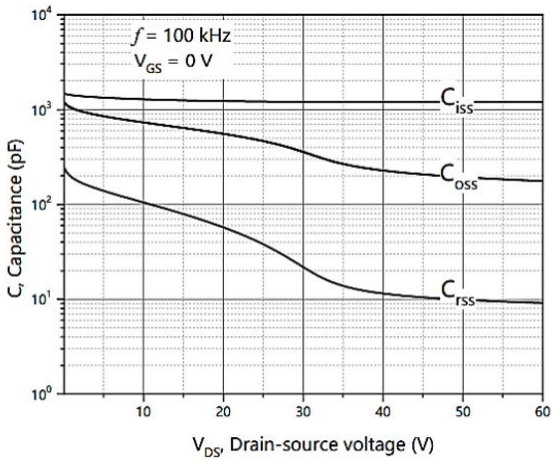


Figure 3. Typ. capacitances

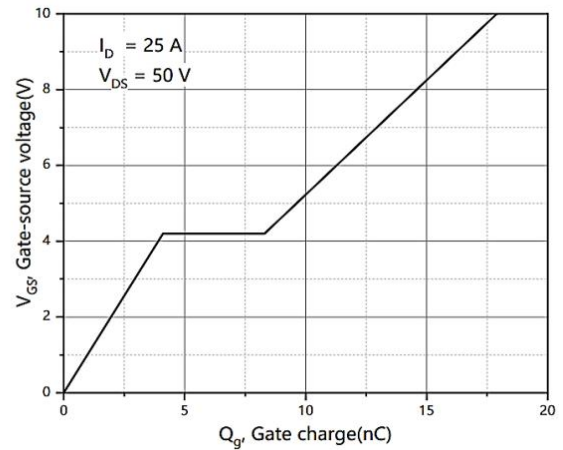


Figure 4. Typ. gate charge

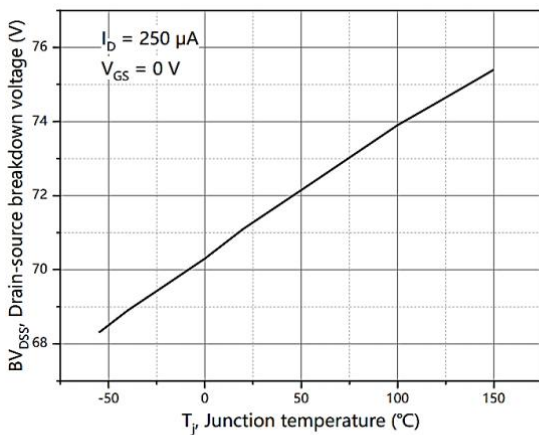


Figure 5. Drain-source breakdown voltage

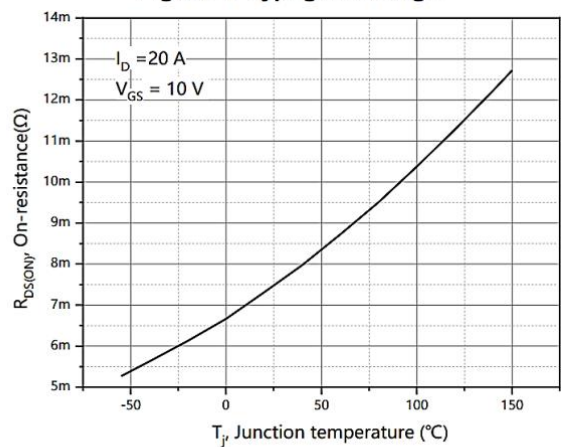


Figure 6. Drain-source on-state resistance

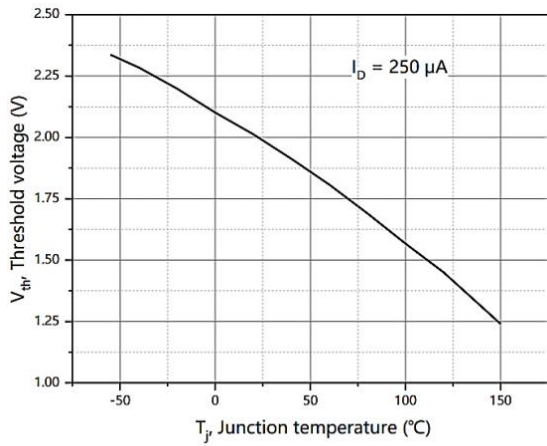


Figure 7. Threshold voltage

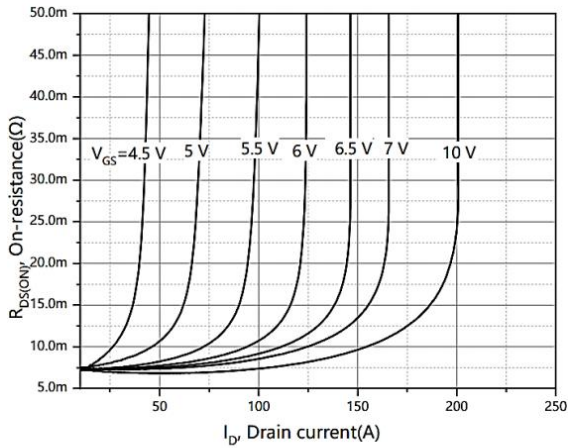


Figure 9. Drain-source on-state resistance

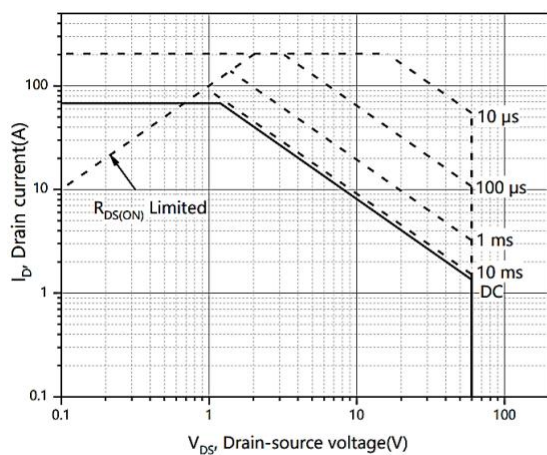


Figure 11. Safe operation area $T_C=25\text{ }^\circ\text{C}$

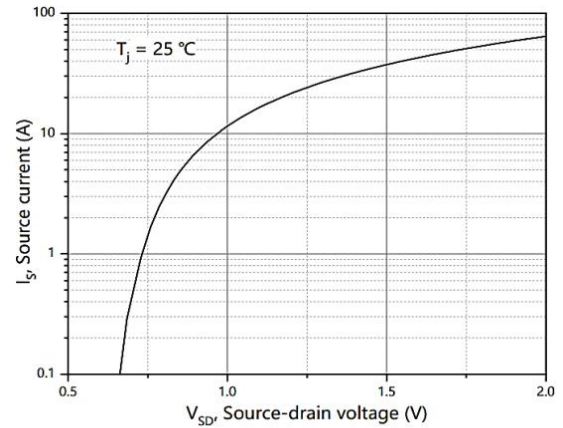


Figure 8. Forward characteristic of body diode

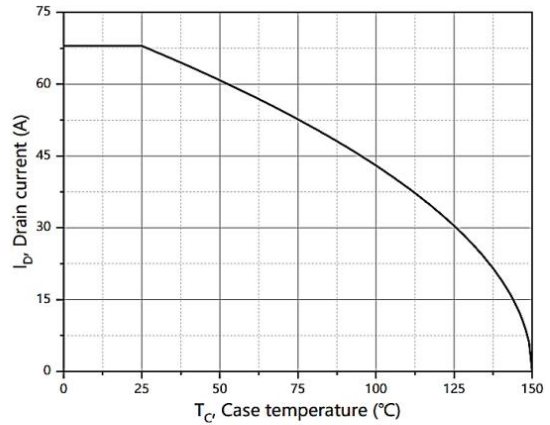


Figure 10. Drain current

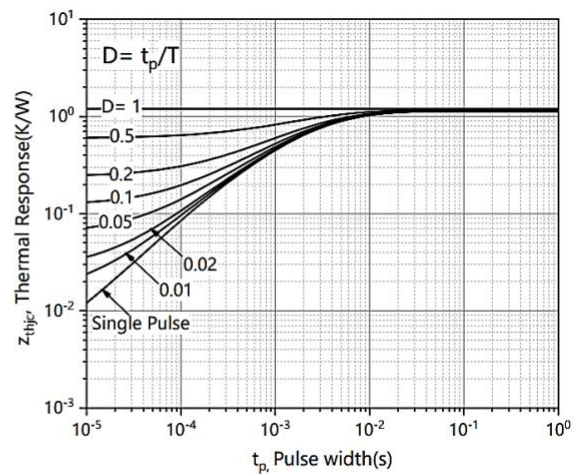
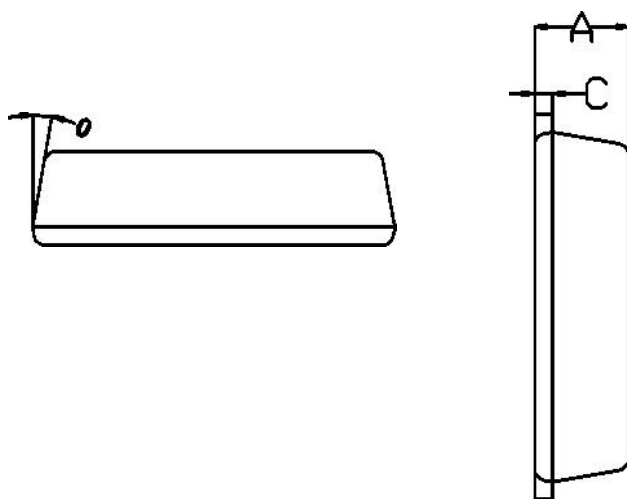
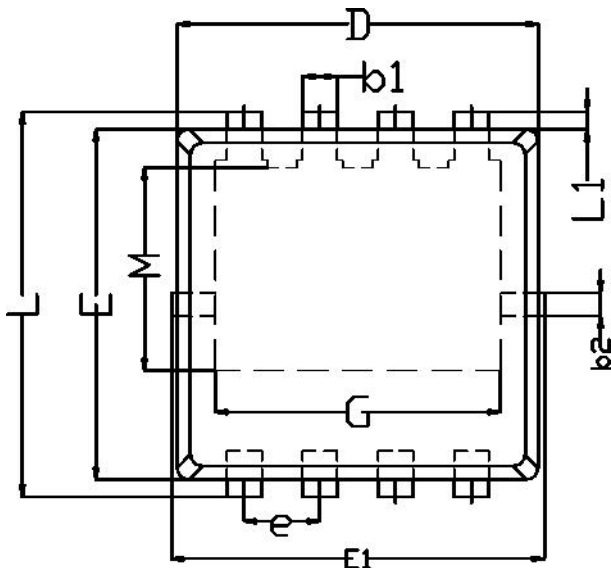


Figure 12. Max. transient thermal impedance



成品外观尺寸/PDFN3*3 Package Information



Syabol	Din in mi		
	Min	Nom	Max
A	0.75	0.80	0.85
LI	0.10	0.15	0.20
b1	0.25	0.30	0.35
b2	0.15	0.20	0.25
C	0.10	0.15	0.20
D	3.050	3.100	3.150
e	0.650OSO		
E	2.950	3.000	3.050
E1	3.150	3.200	3.250
L	3.250	3.300	3.350
M	L685	1.735	1.785
G	2.400	2.450	2.500
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PDFN3*3 Plastic-Encapsulate
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